

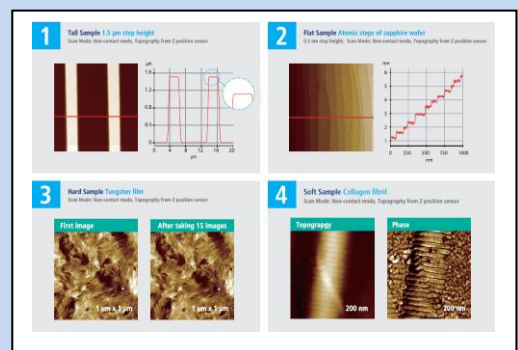
## WORKSHOP ON PARK SYSTEMS ATOMIC FORCE MICROSCOPY ON ITS TREND & ADVANCED TECHNOLOGIES

**The Day** Sept 28, 2016 Wednesday

**Venue** CES SEMINAR HALL,  
BIOENGINEERING LAB,  
3<sup>RD</sup> FLOOR, 'C' WING

**Time** 10am – 5.30pm

- Program**
- Registrations
  - Welcome Address
  - About Park Systems
  - AFM technology trend
  - SICM and Bio AFM application
  - Advanced AFM technology
  - Sample Demo Evaluation
  - Demonstration on AFM Tool



This workshop highlights the advanced features like Scanning Ion Conducting Microscopy (SICM) for life cell imaging, Smartscan, an automated imaging technique that enables a no-vice AFM user to get images that are comparable with those an experienced operator can obtain and PinPoint, Nanomechanical Mode that offers images with resolution to that of a contact mode, without spoiling the sample surface or the AFM Probe. These features will be demonstrated on Park systems AFM NX10 Models at MRDB in IISc.

For further details mail us to “[sales\\_ho@forevision.in](mailto:sales_ho@forevision.in)” or contact

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